

# 2048-BIT SERIAL ELECTRICALLY ERASABLE PROM WITH 2V READ CAPABILITY

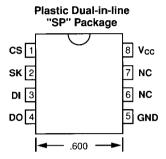
**PRELIMINARY** 

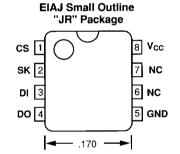
August 1990

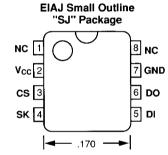
#### **FEATURES**

- State-of-the-Art Architecture
  - Non-volatile data storage
  - Single supply 5V operation
  - Full TTL compatible inputs and outputs
  - 1MHz operation
- Hardware and Software Write Protection
  - Defaults to write-disabled state at power up
  - Software instructions for write-enable/disable
- **Low Power Consumption** 
  - 1mA active (typical)
  - 1μA standby (typical)
- Low Voltage Read Operations
  - Reliable read operations down to 2.0 volts
- Advanced Low Voltage CMOS E<sup>2</sup>PROM Technology
- Versatile, easy-to-use Interface
  - Self-timed programming cycle
  - Automatic erase-before-write
  - Programming Status Indicator
  - Word and chip erasable
  - Stop SK anytime for power savings
- Durable and Reliable
  - 10-year data retention after 10K write cycles
  - Minimum of 10,000 write cycles per word
  - Unlimited read cycles
  - ESD protection

#### PIN CONFIGURATIONS







#### **OVERVIEW**

The IS93C56 is a low cost 2048-bit, non-volatile, serial E<sup>2</sup>PROM. It is fabricated using ISSI's advanced CMOS E<sup>2</sup>PROM technology. The IS93C56 provides efficient non-volatile read/write memory arranged as 128 registers of 16 bits each. Seven 11-bit instructions control the operation of the device, which includes read, write, and mode enable functions. The data out pin (DO) indicates the status of the device during in the self-timed non-volatile programming cycle.

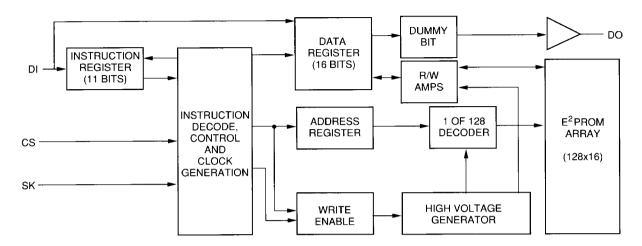
#### **PIN NAMES**

CS Chip Select
SK Serial Data Clock
DI Serial Data Input
DO Serial Data Output
GND Ground
Vcc Power Supply
NC Not Connected

Integrated Silicon Solution, Inc.

680 Almanor Avenue, Sunnyvale, California 94086 (408) 733-4774 FAX (408) 245-4774

#### **BLOCK DIAGRAM**



#### ABSOLUTE MAXIMUM RATINGS

Temperature under bias: IS93C56.......0°C to +70°C IS93C56-I....-40°C to +85°C Storage Temperature....-65°C to +125°C Voltage with Respect to Ground.....-0.3 to +6.5V

NOTE: These are STRESS ratings only. Appropriate conditions for operating these devices are given elsewhere in this specification. Stresses beyond those listed here may permanently damage the part. Prolonged exposure to maximum ratings may affect device reliability.

#### **APPLICATIONS**

The IS93C56 is ideal for high volume applications requiring low power and low density storage. This device uses a low cost, space saving 8-pin package. Candidate applications include robotics, alarm devices, electronic locks, meters and instrumentation settings.

#### **ENDURANCE AND DATA RETENTION**

The IS93C56 is designed for applications requiring up to 10,000 write cycles. It provides 10 years of secure data retention, without power after the execution of 10,000 write cycles.

#### **DEVICE OPERATION**

The IS93C56 is controlled by seven 11-bit instructions. Instructions are clocked in (serially) on the DI pin. Each instruction begins with a logical "1" (the start bit). This is followed by the opcode (2 bits), the address field (8 bits),

and data, if appropriate. The clock signal (SK) may be halted at any time and the IS93C56 will remain in its last state. This allows full static flexability and maximum power conservation.

#### Read (READ)

The READ instruction is the only instruction that outputs serial data on the DO pin. After the read instruction and address have been decoded, data is transferred from the selected memory register into a 16-bit serial shift register. (Please note that one logical "0" bit precedes the actual 16-bit output data string.) The output on DO changes during the low-to-high transitions of SK. (See Figure 3.)

#### Low Voltage Read

The IS93C56 has been designed to ensure that data read operations are reliable in low voltage environments. The IS93C56 is guaranteed to provide accurate data during read operations with V<sub>CC</sub> as low as 2.0V.

## Write Enable (WEN)

The write enable (WEN) instruction must be executed before any device programming can be done. When  $V_{CC}$  is applied, this device powers up in the write disabled state. The device then remains in a write disabled state until a WEN instruction is executed. Thereafter the device remains enabled until a WDS instruction is executed or until  $V_{CC}$  is removed. (NOTE: Neither the WEN nor the WDS instruction has any effect on the READ instruction.) (See Figure 4.)

#### Write (WRITE)

The WRITE instruction includes 16 bits of data to be written into the specified register. After the last data bit has been applied to DI, and before the next rising edge of SK, CS must be brought LOW. The falling edge of CS initiates the self-timed programming cycle.

After a minimum wait of 250ns from the falling edge of CS (tcs), if CS is brought HIGH, DO will indicate the READY/BUSY status of the chip: logical "0" means programming is still in progress; logical "1" means the selected register has been written, and the part is ready for another instruction. (See Figure 5.) (NOTE: The combination of CS HIGH, DI HIGH and the rising edge of the SK clock, resets the READY/BUSY flag. Therefore, it is important if you want to access the READY/BUSY flag, not to reset it through this combination of control signals.) Before a WRITE instruction can be executed, the device must be write enabled (see WEN).

# Write All (WRALL)

The write all (WRALL) instruction programs all registers with the data pattern specified in the instruction. While the WRALL instruction is being loaded, the address field becomes a sequence of DON'T-CARE bits. (See Figure 6.) ERAL is required before WRAL operation.

As with the WRITE instruction, if CS is brought HIGH after a minimum wait of 250ns (tcs), the DO pin indicates the READY/BUSY status of the chip. (See Figure 6.)

## Write Disable (WDS)

The write disable (WDS) instruction disables all programming capabilities. This protects the entire part against accidental modification of data until a WEN instruction is executed. (When VCC is applied, this part powers up in the write disabled state.) To protect data, a WDS instruction should be executed upon completion of each programming operation. (NOTE: Neither the WEN nor the WDS instruction has any effect on the READ instruction.) (See Figure 7.)

#### **Erase Register**

After the erase instruction is entered, CS must be brought low. The falling edge of CS initiates the self-timed internal programming cycle. Bringing CS HIGH after a minimum of tcs, will cause DO to indicate the READ/BUSY status of the chip: a logical "0" indicates programming is still in progress; a logical "1" indicates the erase cycle is complete and the part is ready for another instruction. (See Figure 8.)

### **Erase All (ERAL)**

Full chip erase is provided for ease of programming. Erasing the entire chip involves setting all bits in the entire memory array to a logical "1." (See Figure 9.)

#### **INSTRUCTION SET**

Instruction	Start Bit	OP Code	Address	Input Data
READ	1	10	X(A6-A0)	
WEN (Write Enable)	1	00	11XXXXXX	
WRITE	1	01	X(A6-A0)	D15-D0
WRALL (Write All Registers)	1	00	01XXXXXX	D15-D0
WDS (Write Disable)	1	00	00XXXXXX	
ERASE	1	11	X(A6-A0)	
ERAL (Erase All Registers)	1	00	10XXXXXX	

# IS93C56

# DC ELECTRICAL CHARACTERISTICS

 $T_A = 0^{\circ}C$  to +70°C or -40°C to +85°C for IS93C56,  $V_{CC} = 5V \pm 10\%$ 

			IS930	IS93C56		IS93C56-I	
Symbol	Parameter	Conditions	Min	Max	Min	Max	Units
ICC1	Operating Current CMOS Input Levels	CS = ViH, SK = 1MHz		2		2	mA
ICC2	Operating Current TTL Input Levels	CS = VIH, SK = 1MHz		5		5	mA
IsB	Standby Current	CS = DI = SK =0V		4		4	μА
liL	Input Leakage	VIN = 0V to Vcc, CS, SK, DI	-1	1	-1	1	μА
loL	Output Leakage	VOUT = 0V to Vcc, CS = 0V	-1	1	-1	1	μА
VIL	Input Low Voltage		-0.1	0.8	-0.1	0.8	V
VIH	Input High Voltage		2	Vcc	2	Vcc	٧
V <sub>OL1</sub>	Output Low Voltage	loL = 2.1mA TTL		0.4		0.4	٧
Vон1	Output High Voltage	Іон = -400μA TTL	2.4		2.4		٧
Vol2	Output Low Voltage	IoL = 10μA CMOS		0.2		0.2	٧
<b>V</b> OH2	Output High Voltage	Ioн = -10μA CMOS	Vcc-0.2		Vcc-0.2		V

# **AC ELECTRICAL CHARACTERISTICS**

 $T_A = 0$ °C to +70°C or -40°C to +85°C for IS93C56,  $V_{CC} = 5V \pm 10\%$ 

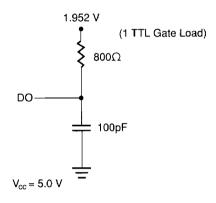
			IS93C56		IS93C56-I		
Symbol	Parameter	Conditions	Min	Max	Min	Max	Units
fsĸ	SK Clock Frequency		0	1	0	1	MHz
tskH	SK High Time		250		250		ns
tskl	SK Low Time		250		250		ns
tcs	Minimum CS Low Time		250		250		ns
tcss	CS Setup Time	Relative to SK	50		50		ns
tois	DI Setup Time	Relative to SK	100		100		ns
tcsн	CS Hold Time	Relative to SK	0		0		ns
tDIH	DI Hold Time	Relative to SK	100		100		ns
tPD1	Output Delay to "1"	AC Test		500		500	ns
tPD0	Output Delay to "0"	AC Test		500		500	ns
tsv	CS to Status Valid	AC Test C <sub>L</sub> = 100pF		500		500	ns
tor	CS to DO in 3-state	CS = VIL		100		100	ns
twp	Write Cycle Time			10		10	ms

# **CAPACITANCE**

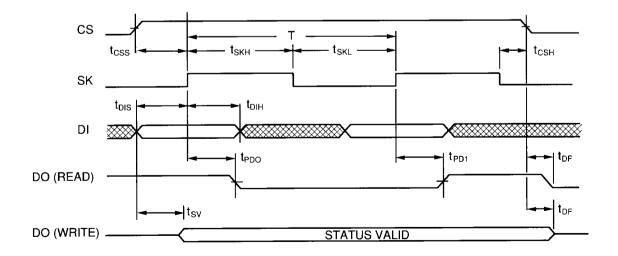
 $T_A = 25^{\circ}C, f = 250KHz$ 

Symbol	Parameter	Parameter Max	
Соит	Output Capacitance	5	pF
Cin	Input Capacitance	5	pF

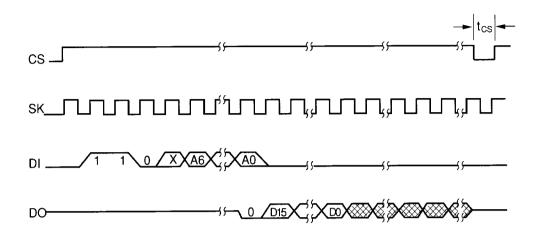
# **FIGURE 1. AC TEST CONDITIONS**



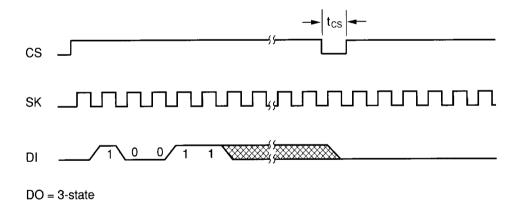
# FIGURE 2. SYNCHRONOUS DATA TIMING



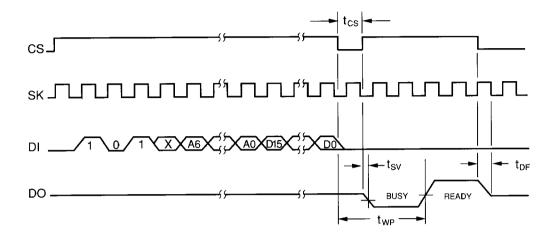
# FIGURE 3. READ CYCLE TIMING



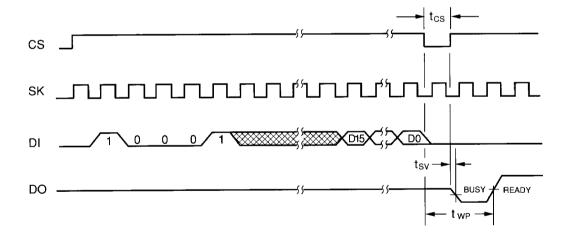
# FIGURE 4. WRITE ENABLE (WEN) CYCLE TIMING



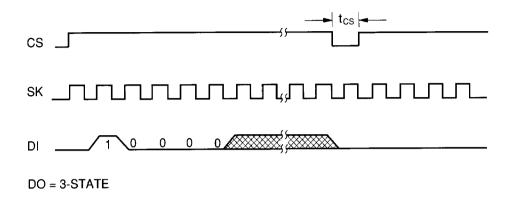
# FIGURE 5. WRITE CYCLE TIMING



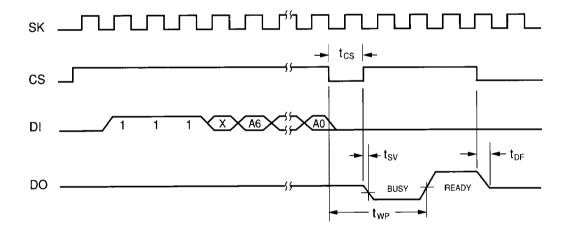
# FIGURE 6. WRITE ALL (WRALL) CYCLE TIMING



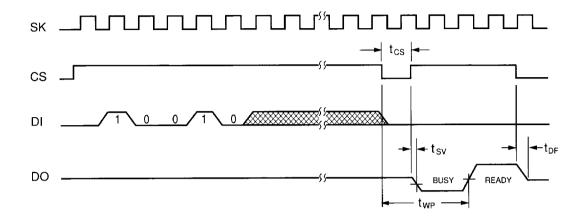
# FIGURE 7. WRITE DISABLE (WDS) CYCLE TIMING



# FIGURE 8. ERASE (REGISTER) CYCLE TIMING

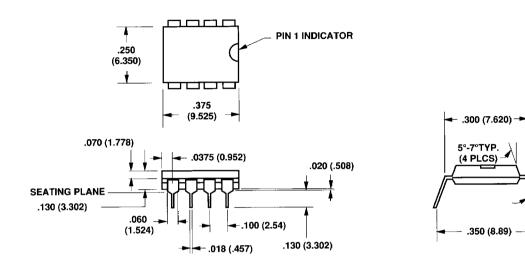


# FIGURE 9. ERASE ALL (ERAL) CYCLE TIMING



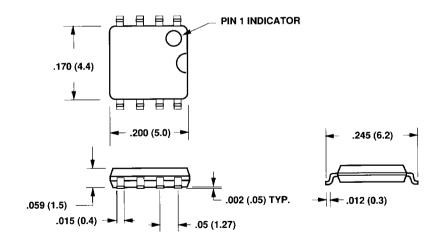
# **PACKAGE DIAGRAMS**

# Plastic Dual-in-line Package (PDIP)



# **EIAJ Small Outline Package**

Package code "SJ" or "JR" specifies pinout\*



.009 (.229)

<sup>\*</sup> See cover page for pinout options

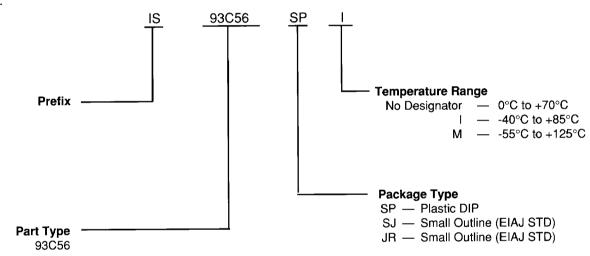
# **ORDERING INFORMATION**

Standard Configurations

Prefix	Part	Package	Temperature
	Type	Type*	Range*
IS	93C56	SP, SJ, JR	Blank, I, M

<sup>\*</sup>CONTACT ISSI FOR YOUR SPECIAL TEMPERATURE AND PACKAGING REQUIREMENTS

# Part Numbers:



# IS93C56

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